

## USB DUAL STACKED A TYPE RECEPTACLE6

#### 1.0 SCOPE

This Specification Covers the USB series product

#### 2.0 PRODUCT DESCRIPTION

The following parts were used in the testing described in this document.

#### 2.1 PRODUCT NAME AND PART NUMBER (S)

Part Numbers	Product Name
67298- 309*	USB CONNECTOR
67298- 409*	USB CONNECTOR

#### 2.2 DIMENSIONS, MATERIALS, PLATINGS AND MARKINGS

Refer to Sales Drawing No.SD-67298-008;

#### 2.3 PRODUCT SPECIFICATION TITLE AND DOCUMENT NUMBER

TITLE: USB CONNECTOR

Document Number: PS-67298-001

#### 3.0 APPLICABLE DOCUMENTS AND SPECIFICATIONS

#### **TESTING PROCEDURES AND SEQUENCES**

Testing is performed sequentially in product specification number "PS-67298-001", Section A.

#### OTHER DOCUMENTS AND SPECIFICATIONS

EIA-364 Electrical Connector/Socket Test Procedures including Environmental Classification MIL-STD-1344 Test Method for Electrical Connectors (Military Standard)

#### 4.0 QUALIFICATION

Laboratory conditions and sample selection are in accordance with EIA-364.

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### 5.0 PERFORMANCE

#### 5.1 ELECTRICAL PERFORMANCE RESULTS

ITEM	DESCRIPTION	TREATMENT	REQUIREMENT	MEAN	MINIMUM	MAXIMUM
	Initial	30 milliohms MAXIMUM	10.8mΩ	$5.8 m\Omega$	17.8mΩ	
		After Durability	30 milliohms MAXIMUM	15.2mΩ	8.1mΩ	20.9mΩ
		After Vibration	30 milliohms MAXIMUM	12.5mΩ	$6.3 m\Omega$	16.9mΩ
			No Discontinuity	Discontinu	ity < 1 micr	osecond
	Contact	After Shock (Mechanical)	30 milliohms MAXIMUM	10.6mΩ	5.9mΩ	20.5mΩ
1	Resistance		No Discontinuity	Discontinuit	y < 1 micros	second
	(Low Level)	After Shock (Thermal)	30 milliohms MAXIMUM	12.7mΩ	6.4mΩ	19.8mΩ
			No Damage	No Visual or Dimensional Change		
		After Thermal Aging	30 milliohms MAXIMUM	14.6mΩ	$7.2 m\Omega$	18.6mΩ
			No Damage	No Visual o	r Dimension	al Change
		After Humidity 1(Steady State)	30 milliohms MAXIMUM	12.4mΩ	6.5mΩ	22.7mΩ
			No Damage	No Visual o	r Dimension	al Change
	la sulstis s	Initial	1000 Meg ohms MINIMUM	angle 1000 Meg ohms		ims
2	Insulation Resistance	After Humidity (Steady State)	500 Volts DC MINIMUM	PASS		
			No Damage	No Visual or Dimensional Change		
		Initial	750 Volts AC MINIMUM	PASS		
_	Dielectric		No Damage	No Visual or Dimensional Change		
3	Withstanding Voltage	After Humidity (Steady State)	750 Volts AC MINIMUM	PASS		
			No Damage	No Visual or Dimensional Change		
4	Capacitance	Initial	2picofarad MAXIMUM		<2picofara	d
5	Temperature Rise	Final	+30 °C MAXIMUM RISE	9.0°C	8.9°C	9.3°C

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#### 5.2 MECHANICAL PERFORMANCE RESULTS

ITEM	DESCRIPTION	TREATMENT	REQUIREMENT	MEAN	MINIMUM	MAXIMUM	
6 Connector Mate and Un-mate Force		Initial Insertion	3.57Kg MAXIMUM	1.52Kg	1.16Kg	1.71Kg	
	Initial un-mating	1.02Kg MINIMUM	2.05Kg	1.86Kg	2.53Kg		
7	Terminal Retention Force	Individual	0.8Kg MINIMUM	1.20Kg	1.15Kg	1.29Kg	
8	Durability	See ITEM 1 [TREATI	See ITEM 1 [TREATMENT: After Durability]				
9	Vibration (Random)	See ITEM 1 [TREATMENT: After Vibration]					
10	Shock (Mechanical)	See ITEM 1 [TREATMENT: After Shock(Mechanical)]					

### **5.3 ENVIRONMENTAL PERFORMANCE RESULTS**

ITEM	DESCRIPTION	TREATMENT	REQUIREMENT			
11	Shock (Thermal)	ee ITEM 1 [TREATMENT: After Shock(Thermal)]				
12	Thermal Aging	See ITEM 1 [TREATMENT	e ITEM 1 [TREATMENT: After Thermal Aging]			
13	Humidity (Steady State)	See ITEM 1 [TREATMENT: After Humidity (Steady State)]				
14	Solder ability	Final	95% Coverage MINIMUM	Coverage > 95%		
15	Solder Resistance	Final	No damage	No Visual or Dimensional Change		

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### 6.0 FIXTURES AND TEST EQUIPMENT

ITEM	DESCRIPTIOM	MANUFACTURING	MODEL
1	Milliohm Meter	GW	GOM-801G
2	Withstanding Voltage/insulation Analyzer	GW	GPI-735
3	Automatic mat and unmated test equipment	AIKOH	AIKOH MODEL-1310N
4	DC POWER SUPPLY	GW	GPS-3030D
5	TEMPERATURE TESTER	KSON	THS-D4C-150
6	SHOCK TESTER	KSON	TSK-D4C-150
7	OVEN TESTER	ETQI	9721
8	VIBRATION TEST SYSTEM	UD	AS15-S452/ST

### 7.0 OTHER INFORMATION

The samples meet the product specification.

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